You have 1 hour to finish the quiz. There are four problems and each is 25% of the total grade. For problem 3, pick one from A, B and C.

Use T=300K unless specified otherwise. Make appropriate assumptions when necessary.

Constants for room temperature Si

$$n_{l} = \frac{10^{10}}{10^{15}} cm^{-3} \qquad E_{g} = 1.14eV \qquad \epsilon_{Si} = 1.04 * 10^{-12}F/cm \qquad q = 1.6 * 10^{-19}C$$

$$h = 6.63 * 10^{-34}m^{2}kg/s = 2\pi h \qquad k_{g} = 1.38 * 10^{-23}m^{2}kgs^{-2}K^{-1} = 8.617 * 10^{-5}eVK^{-1}$$

$$p = hk, E = \frac{h^{2}k^{2}}{2m}, m_{eff} = h^{2}/(\frac{\partial^{2}E}{\partial k^{2}}) \qquad f_{F}(E) = \frac{1}{1 + \exp(\frac{E-E_{F}}{kT})}$$

$$n_{0}p_{0} = n_{l}^{2} = N_{c}N_{v}\exp(-\frac{E_{g}}{kT}) \qquad g_{c}(E) = \frac{4\pi(2m_{h}^{2})^{\frac{3}{2}}}{h^{3}}\sqrt{E-E_{c}}, g_{v}(E) = \frac{4\pi(2m_{h}^{2})^{\frac{3}{2}}}{h^{3}}\sqrt{E-E_{c}}$$

$$n_{0} = N_{c} \exp\left[-\frac{(E_{F}-E_{c})}{kT}\right] = n_{l}\exp\left[\frac{E_{F}-E_{F}}{kT}\right] \qquad g_{c}(E) = \frac{4\pi(2m_{h}^{2})^{\frac{3}{2}}}{h^{3}}\sqrt{E-E_{c}}, g_{v}(E) = \frac{4\pi(2m_{h}^{2})^{\frac{3}{2}}}{h^{3}}\sqrt{E-E_{c}}$$

$$n_{0} = N_{c} \exp\left[-\frac{(E_{F}-E_{c})}{kT}\right] = n_{l}\exp\left[\frac{E_{F}-E_{F}}{kT}\right] \qquad n_{d} + N_{d} - p_{d} = p_{0} + N_{d} - n_{d} \qquad n_{d} = \frac{N_{d}}{1+\frac{1}{2}\exp\left[\frac{E-E_{c}}{kT}\right]}, p_{a} = \frac{N_{d}}{1+\frac{1}{4}\exp\left[\frac{E_{F}-E_{F}}{kT}\right]}$$

$$n_{0} = \frac{N_{d}-N_{a}}{2} + \sqrt{\left(\frac{N_{d}-N_{a}}{2}\right)^{2} + n_{l}^{2}} \qquad |v| = \mu|E|, \qquad \frac{1}{\mu} = \frac{1}{\mu_{lattice}} = \frac{1}{\mu_{limpurity}}$$

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$$\int_{n,diffusion} = qD_{n}\frac{dp}{dx}, J_{p,diffusion} = -qD_{p}\frac{dp}{dx}$$

$$\sigma = q\mu_{n}n + q\mu_{p}p, \rho = 1/\sigma, \tau_{d} = \frac{\epsilon}{\rho}$$

$$1_{p} = D_{p} + \mu_{p}e^{\frac{1}{2}} = \frac{1}{\mu_{p}}e^{\frac{1}{2}}$$

$$0_{p} = \frac{\partial^{2}(\delta p_{n})}{\partial x^{2}} - \mu_{p}E \frac{\partial(\delta p_{n})}{\partial x} + g' - \frac{\delta p_{n}}{\tau_{p0}} = \frac{\partial(\delta p_{n})}{\partial t}$$

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$$V_{bi} = \frac{kT}{q} \ln(\frac{N_{a}N_{d}}{n_{1}^{2}}), V_{B} \approx \frac{\epsilon_{F}E_{r}E_{r}}{2qN_{B}}$$

$$1/2$$

$$1/2 = \frac{dQ'}{dV_{o}} = \frac{q_{F}N_{a}N_{d}}{qV_{o}} = \frac{q_{F}N_{a}N_{d}}{qN_{a}} |_{1/2}^{1/2}$$

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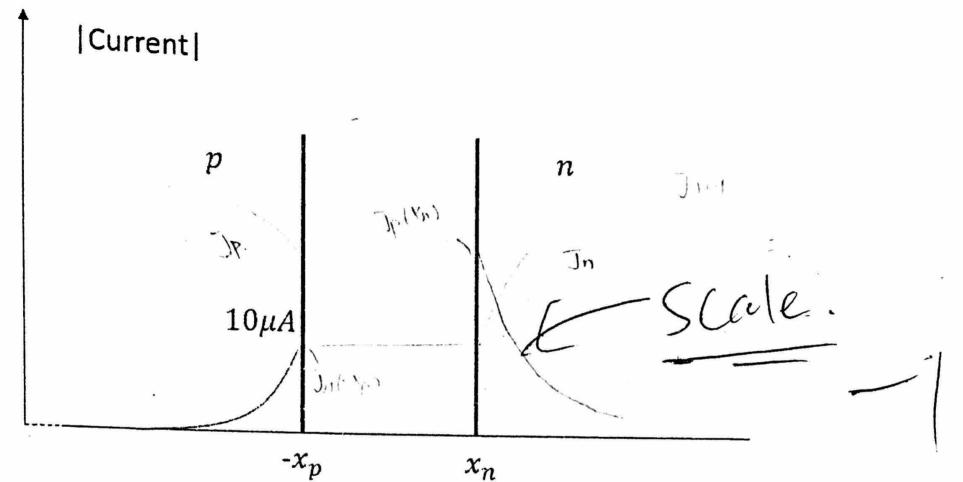
Some solutions for the ambipolar transport equation

$$\delta p(t) = \delta p(0)e^{-t/\tau_{p0}} \qquad \delta p(x) = \delta p(0)e^{-|x|/L_{p}} \\ \delta p(t) = g'\tau_{p0}(1 - e^{-t/\tau_{p0}}) \qquad \delta p(x,t) = e^{-t/\tau_{p0}} * (4\pi D_{p}t)^{-\frac{1}{2}} * exp[-\frac{(x-\mu_{p}E_{0}t)^{2}}{4D_{p}t}]$$

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1. (a) For intrinsic Si, use y-axis for energy and show the relative positions for the conduction band edge, valence band edge and the Fermi level. (b) In the figure from (a), sketch the Fermi-Dirac electrons and holes (total of 5 functions) for electrons and holes, carrier concentration for $E_{Fi} = 0.2eV$, What's the type of the dopant? What are the carrier concentrations now and what is the doping concentration? (d) Repeat (b) for the doped Si in (c).



2. (a) When we calculate the ideal current for a forward-biased diode (ignoring the recombination current), what are the four components of the current? In the figure, we showed one of the four components in the neutral p region. Which component is this one? (b) If $D_n = 25cm^2/s$, $D_p = 10cm^2/s$, $\tau_{n0} = 5*10^{-7}s$ and $\tau_{p0} = 5*10^{-6}s$ and the given current component is $10\mu A$ at $-x_p$ and $N_a = N_d$, what is the total current of the forward-biased diode? Plot the total current in the same figure. (c) Sketch electron current and hole current in the neutral p region, depletion region and neutral n regions based on the information from (a) and (b).

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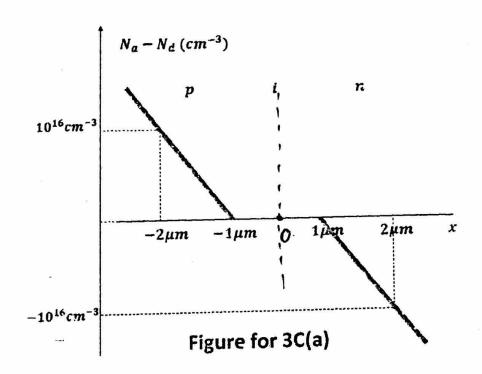
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3. Choose one from problem A, B, C

A: (a) Sketch how carrier mobility changes with temperature and explain. (b) For a moderately doped Si $(N_d \sim 10^{15} cm^{-3})$, sketch its conductivity $(\log(\sigma))$ versus temperature (1/T).

B: Si is used as dopant (N_I) in GaAs. Suppose a fraction of the Si atoms, $\alpha\%$ replaces Ga and the other $1-\alpha\%$ of Si atoms replaces As in the lattice. How will the Fermi level change in the GaAs with respect to α ?

C: (a) For a p-i-n junction with the linear dopant profile as shown in the figure, what's the applied reverse bias if the depletion width is $4\mu m$? (b) Repeat (a) if the i-region is now replaced by metal ($\sigma = \infty$).



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4. Assume that a finite number of electron-hole pairs is generated instantaneously at t=0 and x=0 in an n-type semiconductor, assume the excess carrier generation rate is zero for t>0. (a) Sketch excess carrier concentration with respect to x for $t=t_1, t=t_2, t=t_3$ (3 curves) and $t_3>t_2>t_1>0$ for no external field ($E_0=0$). (b) Repeat (a) for $E_0>0$. (c) Inspired by the result from (b), a very famous experiment is set up to measure the minority carrier mobility, minority carrier diffusion coefficient and minority excess carrier lifetime. What's the name of the experiment and what's its significance? Draw the set up for the experiment. (d) Describe how you can use it to measure the underlined parameters (you might need hint from the equation sheet).